

45875 (OEC1331US)

Patent



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Hyeok-beom LEE

Serial No.: 10/774,469

Filed: February 10, 2004

For: Image-Detectable Monitoring System And  
Method For Using The Same

Group Art Unit: 2643

Examiner: Not Yet Assigned

Confirmation No.: 9123

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In accordance with 37 C.F.R. §§ 1.56 and 1.97-1.98, Applicant hereby transmits copies of the documents listed in the attached Form PTO-1449, which were cited in a search report (copy attached) issued by the European Patent Office with respect to the related European Patent Application No. 04251267.3, filed on March 4, 2004, and which may be deemed material to the examination of the above-identified application.

The present Information Disclosure Statement is being filed prior to the issuance of a first Office Action on the merits, therefore no certification under 37 C.F.R. § 1.97(e) or fee under 37 C.F.R. § 1.17(b) is believed required. Also, each item disclosed was cited for the first time in a communication from a foreign patent office less than three months before the date of the present Information Disclosure Statement. Should any fees be required, the Director is hereby authorized to charge the fee to Deposit Account No. 18-2220.

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The Examiner is requested to consider the attached documents in connection with the above-identified application and to return a copy of Form PTO-1449 to the Applicant with the Examiner's initials in the spaces provided.

Respectfully submitted,

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Form PTO-1449 U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
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## INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

APPLICANT  
Hyeok-beom LEEFILING DATE  
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2643

## U.S. Patent Documents

Examiner Initial	Patent No.	Date	Patentee	Class	Sub-class	Filing Date

## Published U.S. Patent Application

Examiner Initial	Pub. No.	Pub. Date	Patentee	Class	Sub-class	Filing Date
	2002/0190119	12/19/2002	Huffman, John	235	375	

## Foreign Patent Documents or Foreign Patent Applications

	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
						Yes	No
	EP 1260934	11/27/2002	EPA	G06K	9/00	X	

## Other Documents (including Author, Title, Date, Pertinent Pages, etc.)

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
		Hongo, H. et al., "Face and Hand Gesture Recognition for Human-Computer Interaction", September 3, 2000, Pattern Recognition Proceedings, 15 <sup>th</sup> International Conference, Los Alamitos, CA
		Acosta, A. et al., "An Automatic Face Detection and Recognition System for Video Indexing Applications", May 13, 2002, 2002 IEEE International Conference on Acoustics, Speech and Signal Processing, Orlando, FL.
		Albiol, A. et al., "A Simple and Efficient Face Detection Algorithm for Video Database Applications", September 10, 2000, Image Processing Proceedings of the 7 <sup>th</sup> International IEEE Conference.
		Kruger, V. et al., "Gabor Wavelet Networks for Efficient Head Pose Estimation", September 11, 2000, Image and Vision Computing, Proceedings of the 11 <sup>th</sup> British Machine Vision Conference, Bristol, UK.
		Zhengyou, Z. et al., "Comparison Between Geometry-Based and Gabor-Wavelets-Based Facial Expression Recognition Using Multi-Layer Perception", April 14, 1998, Proceedings of the 3 <sup>rd</sup> IEEE International Conference on Automatic Face and Gesture Recognition, Nara, Japan.
		Garcia, C. et al., "Face Detector in Color Images using Wavelet Packet Analysis", June 7, 1999, IEEE International Conference on Multimedia Computing and Systems, 1999.
		Byun, H. et al., "Robust Face Detection and Tracking for Real Life Applications", September 2003, International Journal of Pattern Recognition and Artificial Intelligence.

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw Line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.